

January 2014

# **FQD2N90 / FQU2N90**

## N-Channel QFET® MOSFET

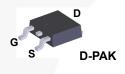
900 V, 1.7 A, 7.2 Ω

## **Description**

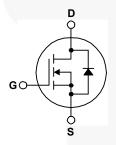
This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

#### **Features**

- 1.7 A, 900 V,  $R_{DS(on)}$  = 7.2  $\Omega$  (Max.) @  $V_{GS}$  = 10 V,  $I_{D}$  = 0.85 A
- Low Gate Charge (Typ. 12 nC)
- · Low Crss (Typ. 5.5 pF)
- 100% Avalanche Tested
- RoHS Compliant







## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter		FQD2N90TM FQU2N90TU_WS FQU2N90TU_AM002	Unit
V <sub>DSS</sub>	Drain-Source Voltage		900	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°	(C)	1.7	Α
	- Continuous (T <sub>C</sub> = 100	)°C)	1.08	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	6.8	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	170	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	1.7	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	5.0	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.0	V/ns
$P_{D}$	Power Dissipation (T <sub>A</sub> = 25°C) *		2.5	W
	Power Dissipation (T <sub>C</sub> = 25°C) - Derate above 25°C		50	W
			0.4	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

## **Thermal Characteristics**

Symbol	Parameter	FQD2N90TM FQU2N90TU_WS FQU2N90TU_AM002	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	2.5	
Ъ	Thermal Resistance, Junction to Ambient (minimum pad of 2 oz copper), Max.	110	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (*1 in² pad of 2 oz copper), Max.	50	

## **Package Marking and Ordering Information**

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQD2N90TM	FQD2N90	D-PAK	Tape and Reel	330 mm	16 mm	2500 units
FQU2N90TU_WS	FQU2N90	I-PAK	Tube	N/A	N/A	75 units
FQU2N90TU_AM002	FQU2N90	I-PAK	Tube	N/A	N/A	75 units

## **Electrical Characteristics** T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	900			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		1.0		V/°(
I <sub>DSS</sub>		V <sub>DS</sub> = 900 V, V <sub>GS</sub> = 0 V			10	μΑ
Zero Gate Voltage Drain Current	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 720 V, T <sub>C</sub> = 125°C			100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
On Cha	aracteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.85 A		5.6	7.2	Ω
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 0.85 A		1.7		S
C <sub>iss</sub>	ic Characteristics Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V,		390	500	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$		45	60	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			5.5	7.0	pF
Switchi	ing Characteristics				1	
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 450 V, I <sub>D</sub> = 2.2 A,		15	40	ns
t <sub>r</sub>	Turn-On Rise Time	$R_{G} = 25 \Omega$		35	80	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	11.6 20 32		20	50	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)		30	70	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 720 V, I <sub>D</sub> = 2.2 A,	/	12	15	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		2.8		nC
$Q_{gd}$	Gate-Drain Charge	(Note 4)		6.1		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Did	ode Forward Current			1.7	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				6.8	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 1.7 A			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.2 A,		400	[	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI <sub>F</sub> / dt = 100 A/μs		1.6	\	μC

- **Notes:** 1. Repetitive Rating: Pulse width limited by maximum junction temperature 2. L = 111 mH,  $I_{AS}$  = 1.7 A,  $V_{DD}$  = 50 V,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25°C 3.  $I_{SD} \le 2.2$  A, di/dt  $\le 200$  A/µs,  $V_{DD} \le BV_{DSS}$ , Starting  $T_{J}$  = 25°C 4. Essentially independent of operating temperature

## **Typical Characteristics**

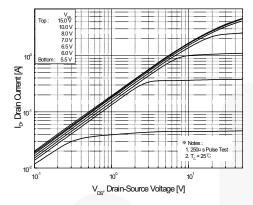


Figure 1. On-Region Characteristics

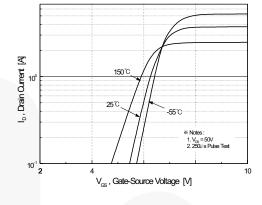


Figure 2. Transfer Characteristics

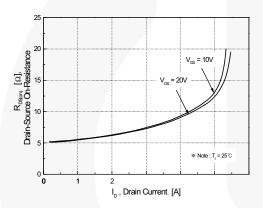


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

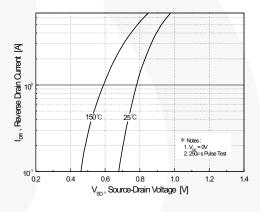


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

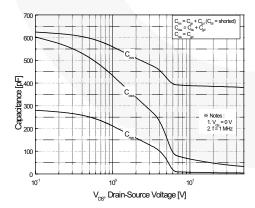


Figure 5. Capacitance Characteristics

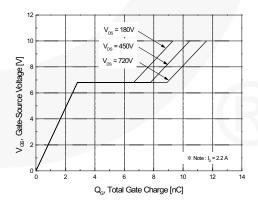


Figure 6. Gate Charge Characteristics

## Typical Characteristics (Continued)

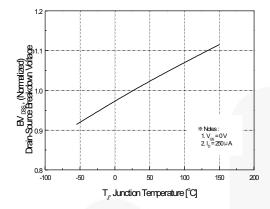


Figure 7. Breakdown Voltage Variation vs. Temperature

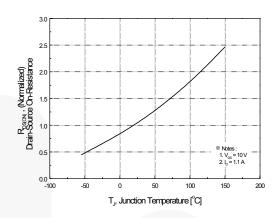


Figure 8. On-Resistance Variation vs. Temperature

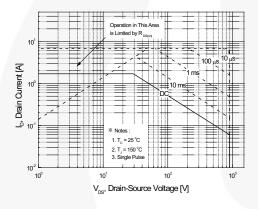


Figure 9. Maximum Safe Operating Area

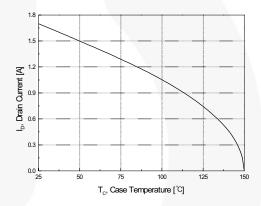


Figure 10. Maximum Drain Current vs. Case Temperature

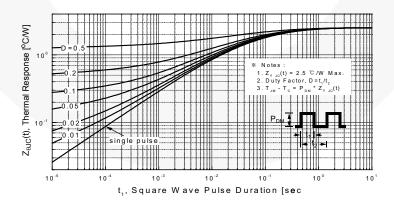


Figure 11. Transient Thermal Response Curve

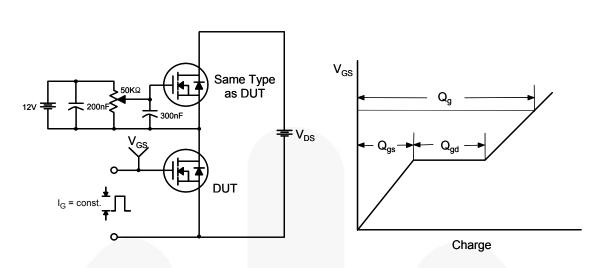


Figure 12. Gate Charge Test Circuit & Waveform

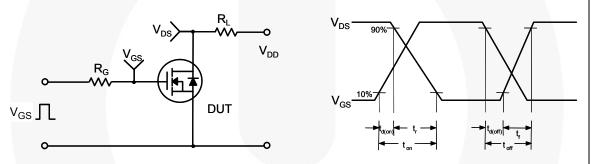


Figure 13. Resistive Switching Test Circuit & Waveforms

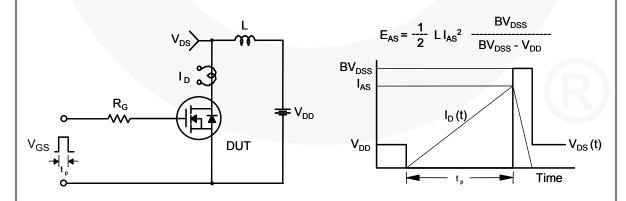


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

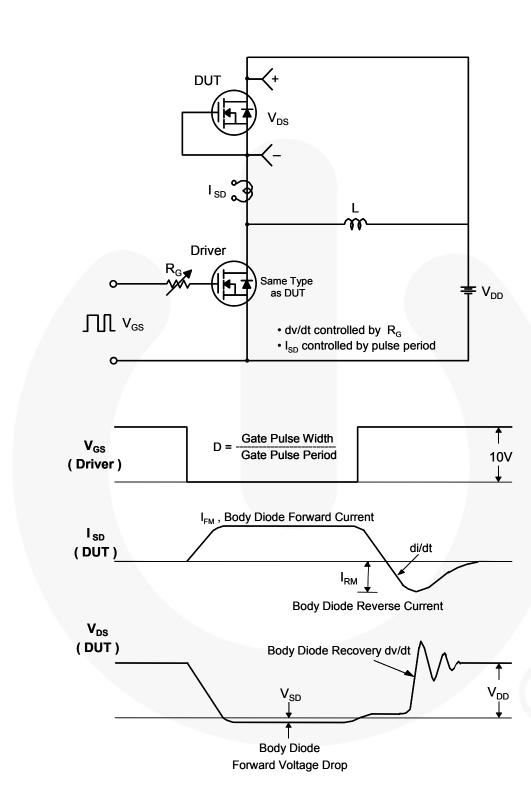


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

## **Mechanical Dimensions**

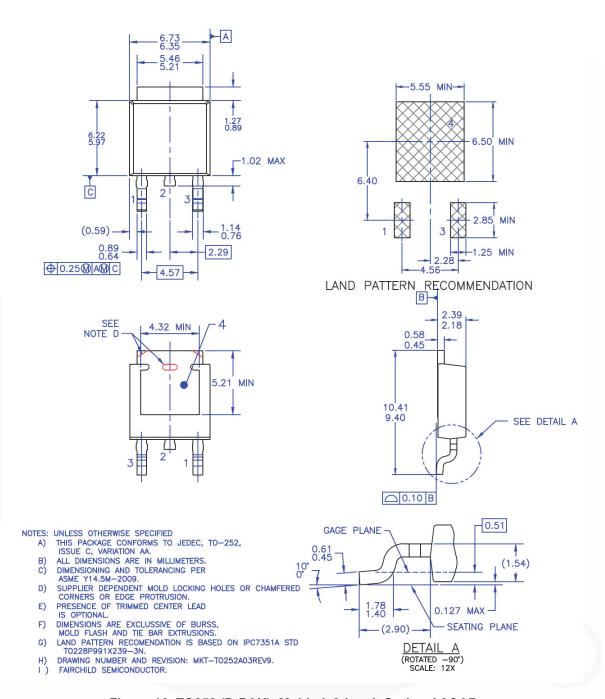


Figure 16. TO252 (D-PAK), Molded, 3-Lead, Option AA&AB

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# **Mechanical Dimensions** C 9.65 8.90 (0.60)2.29 ◆ | 0.25M | AM | C 3 PLCS NOTES: UNLESS OTHERWISE SPECIFIED ALL DIMENSIONS ARE IN MILLIMETERS.

- THIS PACKAGE CONFORMS TO JEDEC, TO-251, ISSUE C, VARIATION AA, DATED SEP 1988.
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

Figure 17. TO-251 (I-PAK), Molded, 3-Lead, Option AA

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